



US00D444720S

(12) **United States Design Patent**  
**Campbell**

(10) **Patent No.:** **US D444,720 S**

(45) **Date of Patent:** **\*\* Jul. 10, 2001**

(54) **NOTCHED ELECTRICAL TEST PROBE TIP**

(75) Inventor: **Julie A. Campbell**, Beaverton, OR  
(US)

(73) Assignee: **LeCroy Corporation**, Beaverton, OR  
(US)

(\*\*) Term: **14 Years**

(21) Appl. No.: **29/127,137**

(22) Filed: **Jul. 31, 2000**

(51) **LOC (7) Cl.** ..... **10-04**

(52) **U.S. Cl.** ..... **D10/80**

(58) **Field of Search** ..... D10/78, 80; 324/72.5,  
324/761, 758, 756, 755, 158 P; 439/482

(56) **References Cited**

**U.S. PATENT DOCUMENTS**

- D. 400,811 \* 11/1998 Swart et al. .... D10/80
- D. 422,518 \* 4/2000 Luebke ..... D10/80

\* cited by examiner

*Primary Examiner*—Antoine Duval Davis  
(74) *Attorney, Agent, or Firm*—Miller Nash LLP

(57) **CLAIM**

The ornamental design for a notched electrical test probe tip, as shown and described.

**DESCRIPTION**

FIG. 1 is a general perspective view of a notched electrical test probe tip showing the new design, wherein the broken line depiction of the shaft is included merely for illustrative purposes and forms no part of the claimed design.

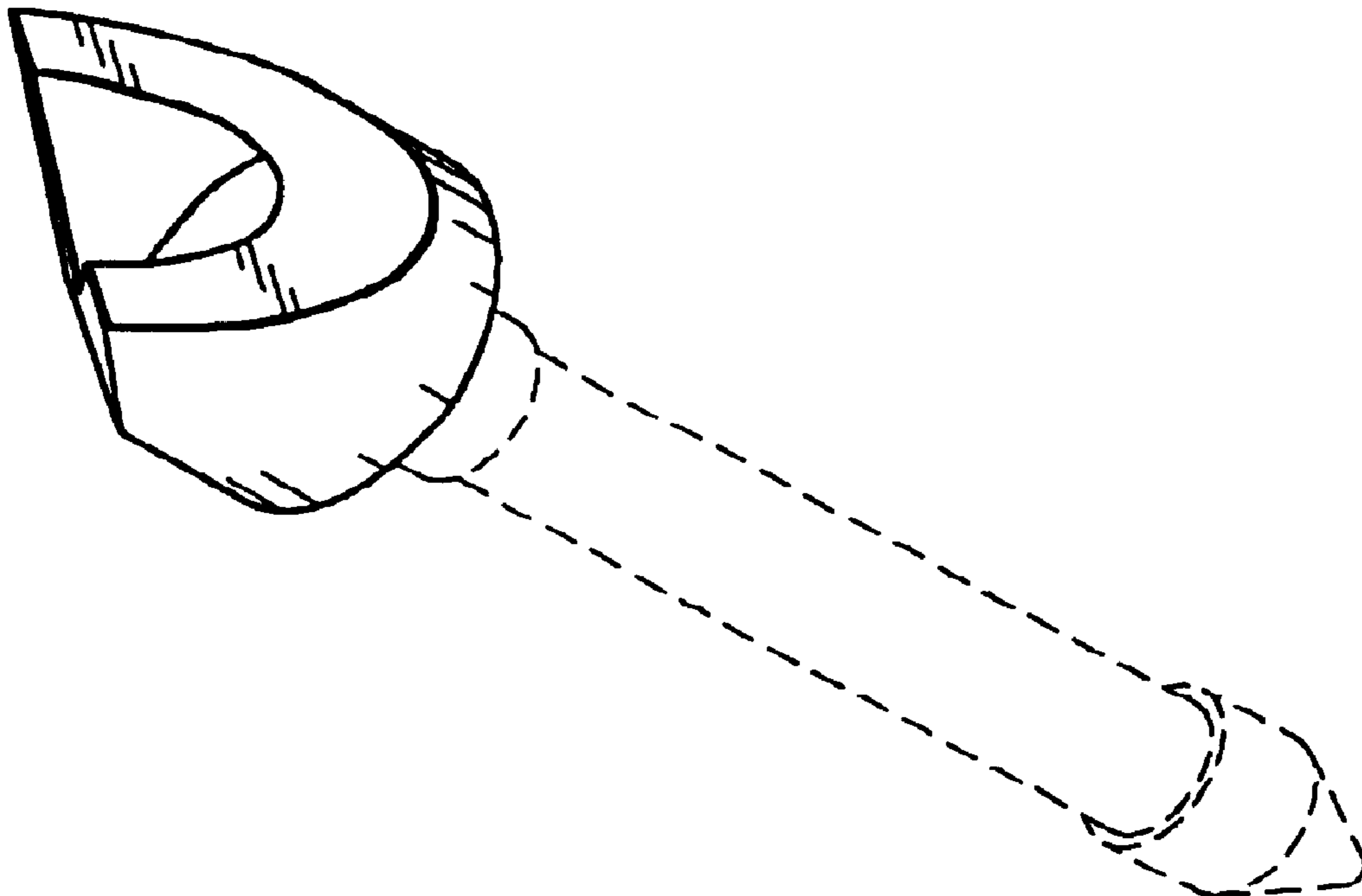
FIG. 2 is a front view of the notched electrical test probe tip, the back view being a mirror image thereof, wherein the broken line depiction of the shaft is included merely for illustrative purposes and forms no part of the claimed design.

FIG. 3 is a right side view of the notched electrical test probe tip, the left side view being a mirror image thereof, wherein the broken line depiction of the shaft is included merely for illustrative purposes and forms no part of the claimed design.

FIG. 4 is a top view of the notched electrical test probe tip; and,

FIG. 5 is a bottom view of the notched electrical test probe tip.

**1 Claim, 2 Drawing Sheets**



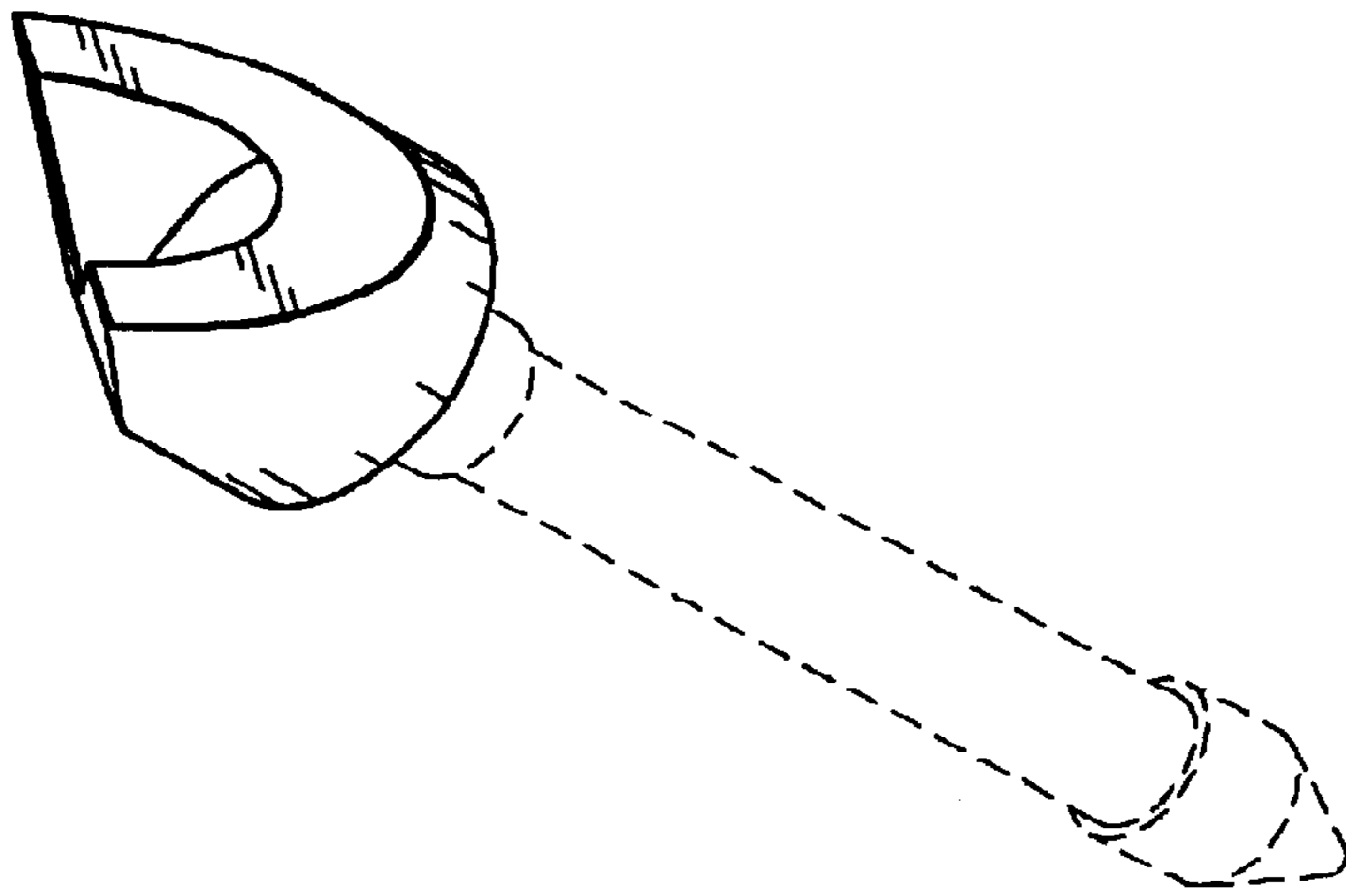


FIG. 1

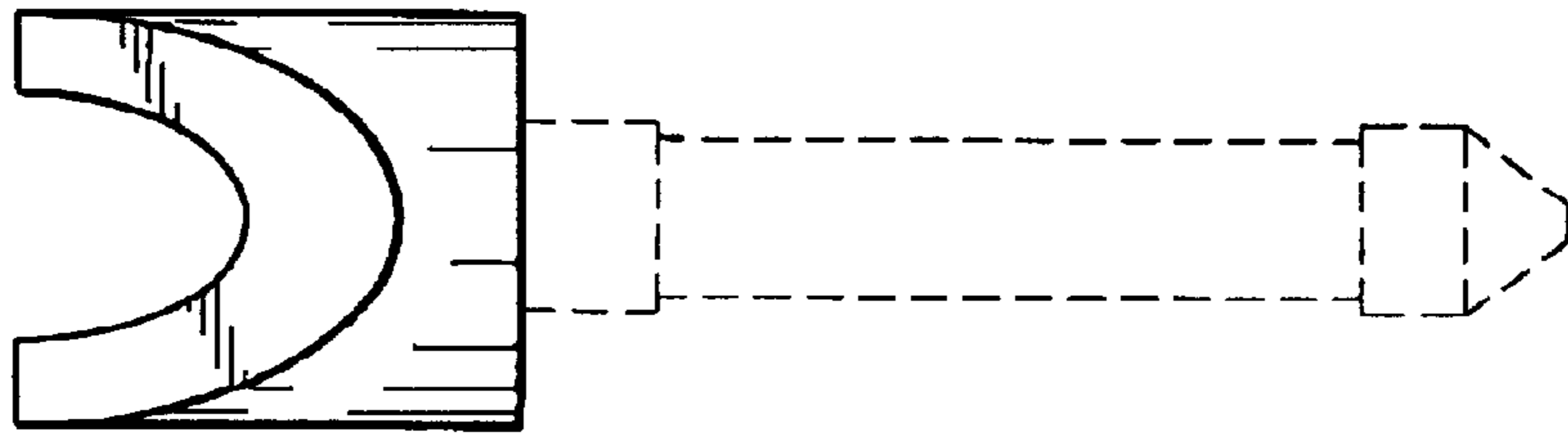


FIG. 2

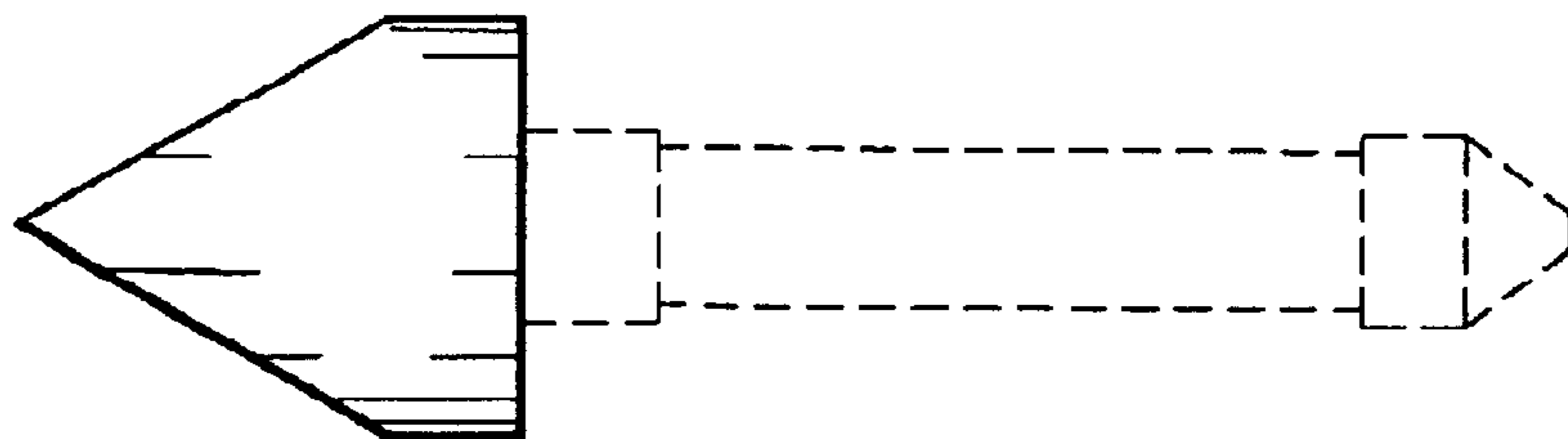
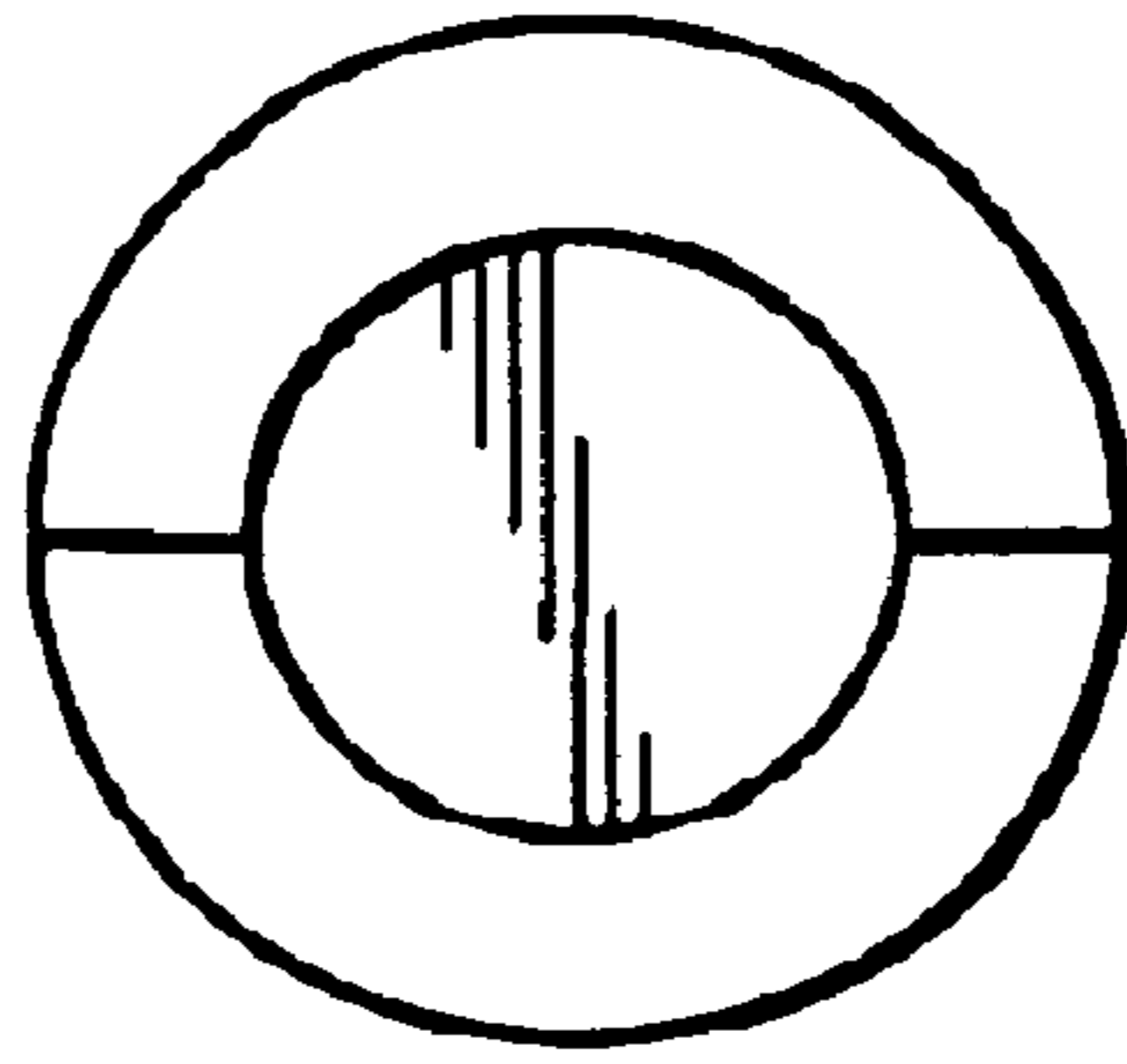
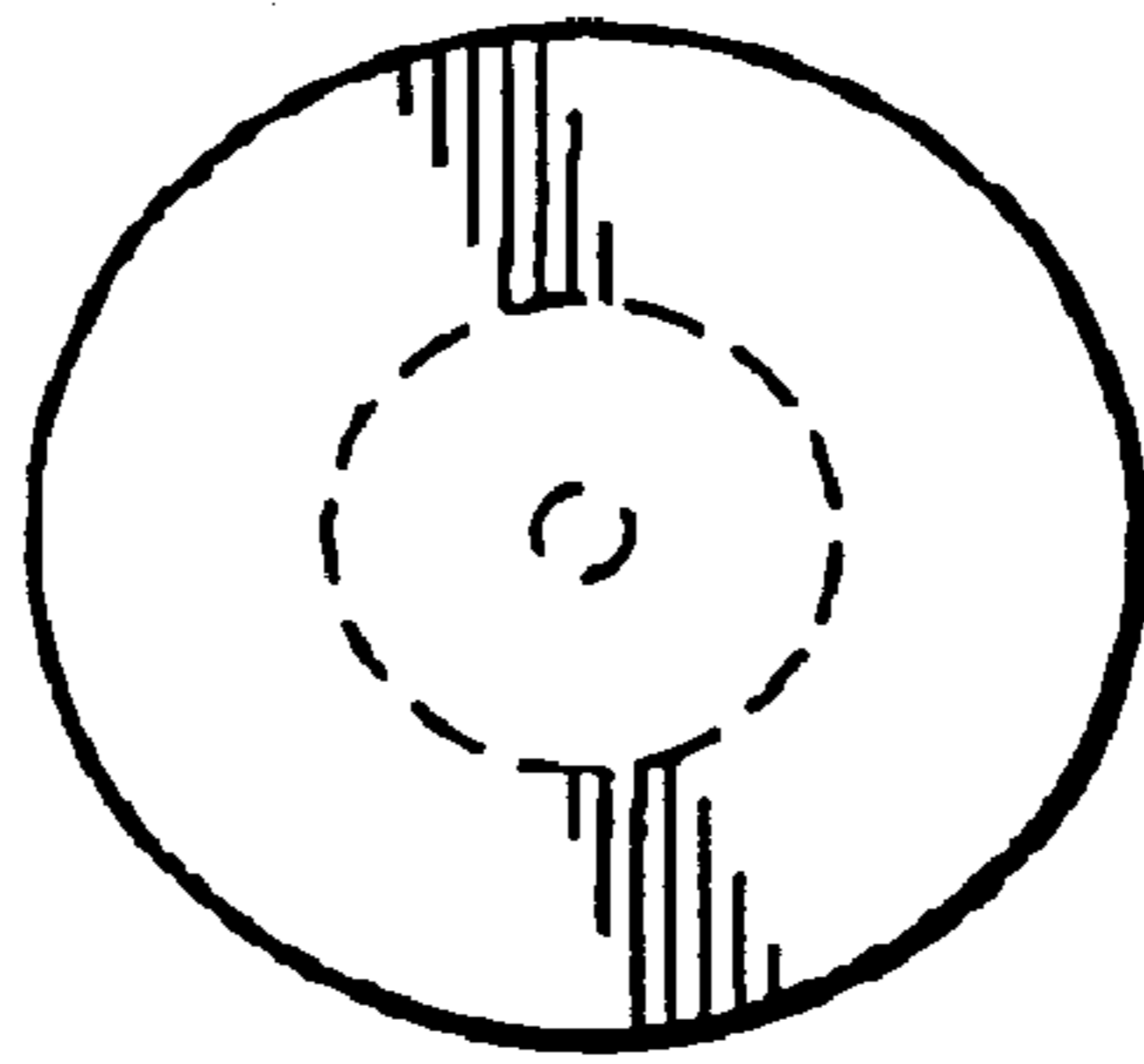


FIG. 3



*FIG. 4*



*FIG. 5*